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22	5,306,644	4/26/94	M	yerholtz et al.	43)		149	
mo	5,571,401	11/5/96		Lewis et al.	Za		18.7	
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79V		11/7/95	Gaiten, et al.	219	544	2000 2000
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

APPLICANT Mansky et al.

65304-039

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Hor	4,423,371	12/27/83	Senturia et al.	324	663	
Tov	4,448,943	5/15/84	Golba et al.	526	59	
70	4,571,543	2/18/86	Raymond et al.	324	425	
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1190	4,710,550	12/1/87	Kranbuehl	57.6	60	
20	4,891,591	1/2/90	Johnston et al.	324	234	
Town /	5,063,081	11/5/91	Cozzette et al.	435	4	
WY .	5,095,278	3/10/92	Hendrick	32Y	687	
182	5,164,319	11/17/92	Hafeman et al.	435	287.1	
res	5,345,213	9/6/94	Semancik et al.	338	34	
in	5,356,756	10/18/94	Cavicchi et al.	430	3/5	
20/	5,491,097	2/13/96	Ribi et al.	436	518	

# FOREIGN PATENT DOCUMENTS

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#### OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

)or	"Thermodynamic Measurements of Magnetic Ordering in Takano, F. Hellman, and A.E. Berkowitz, <a href="Physical Revie">Physical Revie</a> 3451-3454.	
20V	"The Anatomy of a Microcalorimeter," Kim Allen, <a href="http://physics.ucsd.edu/~kallen/Microcal/calorimeter.htm">http://physics.ucsd.edu/~kallen/Microcal/calorimeter.htm</a>	
201	"Heat Capacity Measurements on Small Samples at Low T.H. Geballe, R.L. Greene, R.E. Howard, C.N. King, H.C and R.B. Zubeck, <u>The Review of Scientific Instruments</u> ,	C. Kirsch, K.N. Lee, R.E. Schwall, H.U. Jonas,
Examiner 16	Ulah Saran	Date Considered //-2x-d/

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2	5,532,128	7/2/96	F	Eggers et al.	1 935	6	
nev	5,533,393	7/9/96	I	Bonne et al.	73	335,07	
n	5,534,111	7/9/96	ŀ	locker et al.	216	15	
1/2	5,557,972	9/24/96	J	lacobs et al.	73	256	
MA	5,597,957	1/28/97	Schie	eferdecker et al.	73	ンジン	
W	5,602,393	2/11/97		Gerard	250	338, 4	
m.	5,622,633	4/22/97	O	htsuka et al.	438	/ جي	

## FOREIGN PATENT DOCUMENTS

Heller et al.

Martinis et al.

Strong et al.

Northrup et al.

Mandecki

722

5,632,957

5,634,718

5,635,845

5,639,423

5,641,634

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## OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

w	"Micromechanical Thermogravimetry," R. Berger, H.P. Scandella, E. Meyer, H.J. Guntherodt, <u>Chemical Physics</u> 369.	
Por	"An Ultrahigh Vacuum Single Crystal Adsorption Micro Rev. Sci. Instrum., Vol. 62, No. 9, September 1991, pp.	
194	"Relaxation Phenomena in Dense, Glassy Membranes Pont Changes in Dielectric Properties," R.H.B. Bouma, Th. v. P.F. Mijnlieff, Journal of Membrane Science, Vol. 113,	an den Boomgaard, C.A. Smolders, H. Strathman,
	1200	1 92/102



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e'			Sheet <u>3</u> of <u>16</u>
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m.	5,653,939	8/5/97	Hollis et al.	422	00	
1/2)	5,659,127	8/19/97	Shie et al.	73	31.05	
Tal	5,670,322	9/23/97	Eggers et al.	435	6	
m/	5,739,686	4/14/98	Naughton et al.	324	259	
m/	5,759,493	6/2/98	Raisanen	422	88	
M	5,783,805	7/21/98	Katzmann	219	794	
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#### **OTHER DOCUMENTS**

(Including Author, Title, Date, Pertinent Pages, Etc.)

	(
How	"A Class of Cobalt Oxide Magnetoresistance Materials Discovered with Combinatorial Synthesis," Gabriel Briceno, Hauyee Chang, Xiaodong Sun, Peter G. Schultz, X.D. Xiang, Science, Vol. 270, October 13, 1995, pp. 273-275.
202	"Thermal Conductivity Measurement from 30 to 750 K: the 3ω Method," David G. Cahill, Rev. Sci. Instrum., Vol. 61, No. 2, February 1990, pp. 802-808.
lor	"Thermal Conductivity of a-Si:H Thin Films," David G. Cahill, M. Katiyar, and J.R. Abelson, <u>The American Physical Society</u> , Vol. 50, No. 9, September 1, 1994, pp. 6077-6081.

Examiner: Initial if citation considered, whether or not citation is in conformance with MPSP 603 Draw-line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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MOV	<u>Tech</u>	nol., Vol. 12, No. 4,	Jul/Aug 1994	l, pp. 2549-2553.						
bul	Dan	ombinational Chem Giaquinta, Shenhang	Guan, Eric N	AcFarland, Kyle S	elf. Howar	d Turner	and W	V. Henry W	einburg	.
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Bul			Diethelm Johannsm	ann, J. Appl. Phys.	, Vol. 80, No. 5,	September 1, 1996	i, pp. 2599-2604.		
nal			"A Silicon on Sappl Hellman, J. Marshal						
Hellman, J. Marshall, and T. H. Geballe, Physics, Vol. 107B, 1981, pp. 327-328. Whose, R. "Nanocalorimeter for High Resolution Measurements of Low Temperature Heat Capacities of Thin Films and Single Crystals," Fernando Fominaya, Thierry Fournier, Philippe Gandit, and Jacques Chaussy, Rev.							of Thin Films	$\dashv$	
100			and Single Crystals, Sci. Instrum., Vol. 6				dit, and Jacques (	Chaussy, <u>Rev.</u>	
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#### OTHER DOCUMENTS

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W	"Heat Capacity Cryostat and Novel Methods of Analysis for Small Specimens in the 1.5-10 K Range," E.M Forgan and S. Nedjat, Rev. Sci. Instrum., Vol. 51, No. 4, April 1980, pp. 411-417.
for	"Thermal Conductivity and Diffusivity Measurements in the sub-μs Scale on Centimeter Area Samples Using a Microthermocouple," R. Forster and E. Gmelin, Rev. Sci. Instrum., Vol. 67, No. 12, December 1996, pp. 4246-4255.
Tor	"An AC Calorimeter for Measuring Heat Capacity of Free-Standing Liquid-Crystal Films," R. Geer, T. Stoebe, T. Pitchford, and C.C. Huang, Rev. Sci. Instrum., Vol. 62, No. 2, February 1991, pp. 415-421.
Examiner \$	Date Considered //-25-C/

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rer	Abstract, "Microcalorimetric Study of the Acidic Character of Modified Metal Oxide Surfaces. Influence of the Loading Amount on Alumina, Magnesia, and Silica," A. Gervasini, Langmuier, Vol. 12, 1996, pp. 5356-5364. 1paye. (No and Silica)
100	"Modulated-bath Calorimetry," J.E. Graebner, Rev. Sci. Instrum., Vol. 60, No. 6, June 1989, pp. 1123-1128.
70-/	"Specific Heat of Granular Aluminum Films," R.L. Greene, C.N. King, and R.B. Zubeck, Physical Review B, Vol. 6, No. 9, November 1, 1972, pp. 3297-3304.

Examiner Date Considered

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OTHER DOCUMENTS

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m	Abstract, "Localized Thermal Analysis Using a Mechanical Resistive Probe," A. Hammiche, M. Reading, H.M. Pollock, and M. Song, Rev. Sci. Instrum., Vol. 67, No. 12, December 1996, pp. 4268-4274.							
son	"Nanocalorimeter for Explorations of Mesoscopic Heat Flow," E.A. Henriksen, K.C. Schwab, J.M.							
m	"Experimental Limitations in Impedance Spectroscopy of Materials Systems," G. Hsieh, D.D. Edwards, S.J. Ford, J.H. Hwang, J. Shane, E.J. Garboczi, and T.O. Mason, Mat. Res. Soc. Symp. Proc., Vol. 411, 1996, pp. 3-13. ( 1/2 0.02, //)							
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low		"Heat Capacity Measurements of Sn Nanostructures Usin with 0.2 nJ Sensitivity," S.L. Lai, G. Ramanath, L.H. All 1, January 6, 1997, pp. 43-45.										
mi	8	"High-Speed (10 <sup>4</sup> °C/s) Scanning Microcalorimetry with Ramanath, and L.H. Allen, Appl. Phys. Lett., Vol. 67, N	Monolayer Sensitivity (J/m²)," S.L. Lai, G. o. 9, August 28, 1995, pp. 1229-1231.									
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5,755,942	05/26	/98	Zanzucchi et al.	204		454		
5,788,833	08/04		Lewis et al.	205		787		
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Ø√		S.L. LAI, G. RAMANATH, and L.H. ALLEN "High speed (104°C/S):Scanning Microcalorimetry with monolayer sensitivity (J/m²)" Applied Physics Letters 67 (9) 28 August 1995 pg1229-1231  D.W. DENLINGER, E.N.ABARRA, KIMBERLY ALLEN, P.W. ROONEY, M.T.MESSER, S.K.WATSON AND F. HELLMAN "Thin Film microcalorimeter for heat capacity measurements	
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First Named Inventor	Paul Mansky					
Group Art Unit	2858					
Examiner Name	H. Wachsman					
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<sup>1</sup> Unique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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